

Notice of References Cited	Application/Control No. 10/811,823		Applicant(s)/Patent Under Reexamination YAMANO ET AL.	
	Examiner Mark Eashoo, Ph.D.		Art Unit 1732	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0072545	04-2003	Kusakari et al.	385/101
*	B	US-4,725,453	02-1988	Nakasone et al.	427/163.2
*	C	US-4,795,234	01-1989	Nakasone et al.	385/102
*	D	US-4,814,133	03-1989	Kitagawa et al.	264/1.28
*	E	US-6,068,796	05-2000	Graham et al.	264/1.28
*	F	US-6,728,455	04-2004	Kusakari et al.	385/113
*	G	US-6,928,217	08-2005	Mohler et al.	385/113
*	H	US-7,011,774	03-2006	Risch, Brian G.	264/1.28
*	I	US-4,781,433	11-1988	Arroyo et al.	385/102
*	J	US-5,932,149	08-1999	Schneider, Reiner	264/1.29
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
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	Q					
	R					
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	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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